



3/29/2010

**PRODUCT RELIABILITY REPORT  
FOR**

**DS26521, Rev A2**

**Maxim Integrated Products**

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**Conclusion:**

The following qualification successfully meets the quality and reliability standards required of all Maxim products:

DS26521, Rev A2

In addition, Maxim's continuous reliability monitor program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards. The current status of the reliability monitor program can be viewed at <http://www.maxim-ic.com/TechSupport/dsreliability.html>.

**Device Description:**

A description of this device can be found in the product data sheet. You can find the product data sheet at [http://dbserv.maxim-ic.com/l\\_datasheet3.cfm](http://dbserv.maxim-ic.com/l_datasheet3.cfm).

**Reliability Derating:**

The Arrhenius model will be used to determine the acceleration factor for failure mechanisms that are temperature accelerated.

$$AfT = \exp((Ea/k) * (1/Tu - 1/Ts)) = tu/ts$$

AfT = Acceleration factor due to Temperature  
tu = Time at use temperature (e.g. 55°C)  
ts = Time at stress temperature (e.g. 125°C)  
k = Boltzmann's Constant (8.617 x 10<sup>-5</sup> eV/°K)  
Tu = Temperature at Use (°K)  
Ts = Temperature at Stress (°K)  
Ea = Activation Energy (e.g. 0.7 ev)

The activation energy of the failure mechanism is derived from either internal studies or industry accepted standards, or activation energy of 0.7ev will be used whenever actual failure mechanisms or their activation energies are unknown. All deratings will be done from the stress ambient temperature to the use ambient temperature.

An exponential model will be used to determine the acceleration factor for failure mechanisms, which are voltage accelerated.

$$AfV = \exp(B * (Vs - Vu))$$

AfV = Acceleration factor due to Voltage  
Vs = Stress Voltage (e.g. 7.0 volts)  
Vu = Maximum Operating Voltage (e.g. 5.5 volts)  
B = Constant related to failure mechanism type (e.g. 1.0, 2.4, 2.7, etc.)

The Constant, B, related to the failure mechanism is derived from either internal studies or industry accepted standards, or a B of 1.0 will be used whenever actual failure mechanisms or their B are unknown. All deratings will be done from the stress voltage to the maximum operating voltage. Failure rate data from the operating life test is reported using a Chi-Squared statistical model at the 60% or 90% confidence level (Cf).

The failure rate, Fr, is related to the acceleration during life test by:

$$Fr = X / (ts * AfV * AfT * N * 2)$$

X = Chi-Sq statistical upper limit  
N = Life test sample size

Failure Rates are reported in FITs (Failures in Time) or MTTF (Mean Time To Failure). The FIT rate is related to MTTF by:

$$\text{MTTF} = 1/\text{Fr}$$

NOTE: MTTF is frequently used interchangeably with MTBF.

The calculated failure rate for this device/process is:

**FAILURE RATE:**                      **MTTF (YRS):**            **116521**            **FITS:**                      **1.0**  
**DEVICE HOURS:**            **935282237**            **FAILS:**                      **0**

Only data from Operating Life or similar stresses are used for this calculation.

The parameters used to calculate this failure rate are as follows:

**Cf: 60%**                      **Ea: 0.7**                      **B: 0**                      **Tu: 25 °C**                      **Vu: 3.5 Volts**

The reliability data follows. At the start of this data is the device information. The next section is the detailed reliability data for each stress. The reliability data section includes the latest data available and may contain some generic data. **Bold** Product Number denotes specific product data.

**Device Information:**

Process:                                      2P, 4M,0.35um,Sil.P1,P2Cap,Ti/TiN M1-M4,BPSG,Masked  
Passivation:                                  Passivation w/Nov TEOS Oxide-Nitride  
Die Size:                                        155 x 270  
Number of Transistors:                      582000  
Interconnect:                                  Aluminum / 0.5% Copper  
Gate Oxide Thickness:                        75 Å

**ESD HBM**

DESCRIPTION	DATE	CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
ESD SENSITIVITY	1005	<b>DS26521</b>	QN100253A JESD22-A114 HBM 500 VOLTS	1	PUL'S	3	0
ESD SENSITIVITY	1005	<b>DS26521</b>	QN100253A JESD22-A114 HBM 1000 VOLTS	1	PUL'S	3	0
ESD SENSITIVITY	1005	<b>DS26521</b>	QN100253A JESD22-A114 HBM 2000 VOLTS	1	PUL'S	3	0
ESD SENSITIVITY	1005	<b>DS26521</b>	QN100253A JESD22-A114 HBM 4000 VOLTS	1	PUL'S	3	0
ESD SENSITIVITY	1005	<b>DS26521</b>	QN100253A JESD22-A114 HBM 8000 VOLTS	1	PUL'S	3	0
<b>Total:</b>						<b>0</b>	

**LATCH-UP**

DESCRIPTION	DATE	CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
LATCH-UP I	1005	<b>DS26521</b>	QN100253A JESD78A, I-TEST 85C			6	0
LATCH-UP V	1005	<b>DS26521</b>	QN100253A JESD78A, V-SUPPLY TEST 125C			6	0
<b>Total:</b>						<b>0</b>	

**OPERATING LIFE**

DESCRIPTION	DATE	CODE/PRODUCT/LOT	CONDITION	READPOIN	QTY	FAILS	FA#
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HIGH TEMP OP LIFE	0542	<b>DS26521</b>	QN064481B	125C, 3.5 VOLTS	192	HRS	45	0
HIGH TEMP OP LIFE	0604	DS26522	QL064481BC	125C, 3.5 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0617	DS3184	QS069028AF	125C, 3.6 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0617	DS3184	QS069028A	125C, 3.6 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0617	DS3184	QS069028A	125C, 3.6 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0618	DS2155	QK068011A	125C, 3.5 VOLTS	1000	HRS	77	0
HIGH TEMP OP LIFE	0620	DS26528	QK060309A	125C, 3.5 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0632	DS26334	QK064057B	125C, 3.5 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0632	DS26303	QN066205A	125C, 3.5 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0641	DS3254	QK072332A	125C, 3.5 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0650	DS26522	QL064481AB	125C, 3.5 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0650	DS26522	QL064481AC	125C, 3.5 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0716	DS26900	QN077106B	125C, 3.5 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0811	DS26303	QN080344B	125C, 3.5 VOLTS	1000	HRS	45	0
HIGH TEMP OP LIFE	0913	DS2155	QK097040A	125C, 3.5 VOLTS	1000	HRS	77	0
HIGH TEMP OP LIFE	0913	DS2155	QK096061A	125C, 3.5 VOLTS	1000	HRS	77	0
HIGH TEMP OP LIFE	0916	DS2155	QK098054A	125C, 3.5 VOLTS	1000	HRS	77	0
HIGH TEMP OP LIFE	0931	DS26528	QP099206A	125C, 3.5 VOLTS (PSA)	1000	HRS	45	0
HIGH TEMP OP LIFE	0931	DS26528	QP099206A	125C, 3.5 VOLTS (PSA)	1000	HRS	45	0
HIGH TEMP OP LIFE	0931	DS26528	QP099206A	125C, 3.5 VOLTS (PSA)	1000	HRS	45	0

**Total: 0**

**FAILURE RATE: MTTF (YRS): 116521 FITS: 1.0**  
**DEVICE HOURS: 935282237 FAILS: 0**